

Class	Subclass	
ISSUE CLASSIFICATION		

BEST AVAILABLE COPY

U.S. UTILITY Patent Application

O.I.P.E.	PATENT DATE
AD SCANNED KE3 Q.A. Tm	

APPLICATION NO. 09/883449	CONT/PRIOR	CLASS 714	SUBCLASS 763 744	ART UNIT 2133	EXAMINER T. H. HUNG
------------------------------	------------	--------------	-----------------------------------	------------------	------------------------

APPLICANTS
Nai-Yin Sung
Ming-Chyuan Chen

TITLE
Method to verify the performance of bist circuitry for testing embedded memory

PTO-2040
12/89

ISSUING CLASSIFICATION

ISSUING CLASSIFICATION															
ORIGINAL				CROSS REFERENCE(S)											
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)										
INTERNATIONAL CLASSIFICATION															

☐ Continued on Issue Slip Inside File Jacket

<input style="width: 30px; height: 20px; border: 1px solid black;" type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.	_____ (Assistant Examiner) _____ (Date)			NOTICE OF ALLOWANCE MAILED	
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____ _____ _____	_____ (Primary Examiner) _____ (Date)			ISSUE FEE	
				Amount Due	Date Paid
<input type="checkbox"/> The terminal ____ months of this patent have been disclaimed.	_____ (Legal Instruments Examiner) _____ (Date)			ISSUE BATCH NUMBER	
WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.					

Form **PTO-438A**
(Rev. 6/89)

FILED WITH: ☐ DISK (CRF) ☐ FICHE ☐ CD-ROM
(Attached in pocket on right inside flap)